Sea	t No.:	Enrolment No GUJARAT TECHNOLOGICAL UNIVERSITY	
		M.E. SEMESTER III-EXAMINATION – WINTER 2015	
	•	code: 2732605 Date: 04/12/20	)15
Tin	ne: 2:	Name: VLSI Test principles and Architectures 30 PM to 5:00 PM Total Marks: 7 tions:	0
	1. 2.	Attempt all questions.  Make suitable assumptions wherever necessary.  Figures to the right indicate full marks.	
Q.1	(a) 1. 2. 3. 4. 5. 6. 7.	Do as Directed: Compare Yield and Reject Rate. Explain Scan Stitching in brief in design and testability. Briefly explain event-driven simulation. Define Golden Signature. Define robustly testable path. Briefly explain IDDQ Testing. Define One-Hot Skewed-Load.	07
	(b)	Consider the combinational logic circuit in following figure. How many possible single stuck-at faults does this circuit have? How many possible multiple stuck-at faults does this circuit have? How many collapsed single stuck-at faults does this circuit have?	07
Q.2	(a) (b)	Discuss test point insertion in DFT.  Explain logic simulation for design verification.	07 07
	<b>(b)</b>	<b>OR</b> List out commonly used gate and wire delay models and describe any two of these.	07
Q.3	(a) (b)	Draw and explain typical scan design flow. Explain Random Test generation.	07 07
Q.3	(a) (b)	OR Briefly explain event driven simulation. Explain PODEM algorithm (No need to separately write Pseudo codes).	07 07
Q.4	(a) (b)	Draw structure of Standard and Modular LFSR and compare both with example. What is Output Response Analysis? Explain different output response compaction techniques.  OR	07 07
Q.4	(a) (b)	Briefly explain Untestable Fault Identification. Draw and explain snap-shot scan design architecture.	07 07
Q.5	(a)	Classify the BIST techniques and draw block diagram of logic BIST system and	07

explain it.

Q.5

**(b)** Define Hazard and explain static Hazard detection.

(b) Discuss Spectrum-Based ATPG.

(a) List out BIST design rules and explain any three in detail.

OR

**07** 

**07**